

A Few Microscopical Techniques for the Characterization of Materials /

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IMS

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Abstract

Three techniques will be discussed to illustrate microscopy as an invaluable tool in material characterization. The first considers that one often seeks to differentiate one component from another or even from the matrix. An old and all but forgotten technique from the 1890s called Rheinberg illumination provides a simple way to accomplish this. Experienced metallographers can observe a cross-sectional sample and qualitatively determine the general directional orientation of a grain or sets of grain. The potential value of knowing grain orientation in regards to understanding material properties (or for interpreting forces having acted on a sample) has resulted in the recent rise of Electron Back-Scatter Diffraction (EBSD) as a technique to provide semi-quantitative to quantitative data in this area of research. A poor man's alternative to EBSD can be had using multi-image reflected polarized light microscopy which will be shown. Similarly, the ability to convey technical information on characterization to others, both quickly & efficiently often rests in representing a, enormous amount of visual information simply, clearly and distinctly. The last technique demonstrated will involve stacking images to create 3D depth-of-field delivery to aid in this pursuit.

Three Techniques

- 1. Rheinberg Illumination
- 2. Grain orientation determination
- 3. 3D depth-of-field

1.0 Rheinberg Illumination (1896)

- Rheinberg, J. "On the addition to methods of micro research by new way of optically produced colour contrast (as communicated by E.M. Nelson)," Journal of the Royal Microscopical Society, pp 373– 388, 1896.
- Rheinberg, J. "Note on Coloured Illumination," The Journal of the Quekett Microscopical Club, 2:6, pp 346–347, 1897.
- Rheinberg, J. "Note on a New Modification of Double Colour Illumination," *The Journal* of the Quekett Microscopical Club, 2:6, pp 438–438, 1897.
- Rheinberg, J. "Notes on Colour-Illumination with Special Reference to the Choice of Suitable Colours," *Proceedings of the Royal Microscopical Society*, 19:2, pp 142–146, 1899.



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Havics, Contrast Methods in Microscopy, Rheinberg Illumination, Microscope, 62, 4, 157-169, 2014 4



Darkfield

Reflected Darkfield









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Reflected Darkfield Setup





Option 2: Sandwich Rheinberg



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Brightfield



Quick & Dirty prep of Plumbing fitting, unetched © 2015 A Havics

Darkfield



Sandwich Rheinberg: Blue DF Rfl, Red Oblique





Rheinberg Red & Blue Extracts



Commercial Sandwich Rheinberg, aka, "Bichromatic"



http://www.spectrosci.com/products/product/t2fmq500/#features





Continuous Spun FG Composite



Bl & Red

G of RGB Extracted





Benefits

- Visual Separation by Highlighting
- Digital Separation
- Reduces severe contrast by Darkfield
- Less visual fatigue

$$\phi = t^* \Delta \hat{n}$$

 $t = thickness$
 $\hat{n} = refractive index$
 $\hat{n} = n + ik$

$$I \propto \phi^2$$

Havics, Contrast Methods in Microscopy, Rheinberg Illumination, Microscope, 62, 4, 157-169, 2014

2.0 Grain orientation determination

A Cheap Man's EBSD A Poor Man's EBSD A Very Po Man's EBSD





Reflected PLM

$$R = rac{(n-n')^2 + k^2}{(n+n')^2 + k^2}$$

R = Reflectance (fraction)
n = index of refraction of material
n' = index of refraction of medium (air)
k = absorption coefficient of material



Limitations: Angle of Incidence Effect



Wilsey, The Reflection Coefficients of Metals for the Polarized Components of Light, Phys Rev, 8, 4, 391-401, 1916

Limitations: Wavelength Response



Wilsey, The Reflection Coefficients of Metals for the Polarized Components of Light, Phys Rev, 8, 4, 391-401, 1916



Limitations: Light Source



Tarkian, A new miniphotometer for teaching and routine work in ore microscopy, Min Mag, 40, 97-103, 1975

Limitations: Difference in Polishing



FIG. 2. Reflection spectra of (a) gold and (b) copper with surfaces polished in different ways. (a) \bigcirc electrolytically polished, \triangle cut with the microtome, X alumina polished, \square from Otter [6]. (b) \bigcirc electrolytically polished, \triangle cut with the microtome, + diamond polished, X electromechanically polished, × alumina polished, \square from Otter [6].

Petzow, Application of microreflection in metallography, Metallography, 6, 3, 249-260, 1973



Answer

- Same Scope
- Same light source at same voltage
- Same Objective between samples
- Same Preparation Processes
- Ref material (ex. Pyrite)
- Same Camera & Settings
 - F-Stop, Shutter speed

Ways to Differentiate Direction Qualitatively

- Polarized Light Crossed Polarized Light vs Parallel Polarized Light
 Parallel Polarized Light
- Color Ratios [R:B]
- Texture Etching
- Color Etching
 - material oxide
 - oxide or chemical deposition

Isotropic

Isotropic

Not New: Aluminum



FIG. 2. The variation (schematic) of the intensity I with the angle of rotation θ of the grain around its normal. Solid line = polarizer and analyzer exactly crossed; broken line = polarizer and analyzer not exactly crossed.



Saetre, Variation in polarized light intensity with grain-orientation in anodized aluminum, Metallography, 19, 3, 345-357, 1986

Aluminum



FIG. 2. Specimen electropolished and anodized, viewed with polarized light, showing two microhardness indentation marks.

Ferran, Metallographic preparation and Kossel line studies of aluminum, Metallography, 3, 4, 441-450, 1970

Zinc



Figure 1: (a) Zinc specimen observed with polarized light. (b) Same area as (a) but observed with unidirectional laser oblique illumination (ULOI). HFW = 760µm



Favret, Comparison of ULOI and Polarized Light Microscopy of Materials , UK Micro Microanal, 20, 5, 27-29, July 2001

New Aspects:

- Digital Separation
- Digital Calculations, e.g., MATLAB
- Digital (programmed) Orientation Representation
- Microspectrophotometry



FOURTH ORDER

2.00 2,100 2,200

1.705 1.80 2.300

THIRD ORDER



at Weld



XPL



Note: Recommend circular polarized light





Etch: Klemm

Orientation



3.0 3D depth-of-field

• What is the value of a 3D Object?



Some Benefits, but not always

- Jansen, et al.: Evaluating the efficiency of physical visualizations, Proc 2013 Ann Conf Human Factors in Comp Sys, 2593-1602, 2013
- Alper et al.: Stereoscopic highlighting, 2d graph visualization on stereo displays, IEEE Trans Vis Comp Graphics, 17, 12, 2325-2333, 2011.
- Ramachandran, et al.: Mayavi: a package for 3D visualization of scientific data



Power Usage, by GE, 1935





Discussion here: Micro vs. Macro

- Photomacrography reproduction ratios >1:1
- Photomicrography >>>1:1



Stereo & Dissecting





Optical Arrangement

Comparison of CMO and Greenough Stereomicroscope Designs



"3D" Representations

- Stereo Scope
- Stereo Pair Prints
- Anaglyphs ['anə,glifs]
 Red-Blue or Red-Green
- 3D Stacking



Weaver, Tricks of the Trade, The Universal Tilting Mouse Stage, Microscope, 51, 4, 221-224, 2003

Tilting Stage



McCrone, Walter: Stereophotomicography Using the Tilting Stage. Microscope, 14, 11, 429-440, 1965



Depth of Field (DOF)



Bloss, F. Donald: *An Introduction to the Methods of Optical Crystallography*, 1961.





How to estimate $\Delta Depth$ for Slices









Fracture Pair (ca. 6 degree)



LR Pair



on paper Center of images should be 63-65 mm apart





Set of images to Stack













Z-Stacking



First in Series

Last in Series



1

Stack of 17 images





Stack of 17 images

Cinc Fracture



3D Composite



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Questions?



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